

ZEISS

ZEISS is a leading international technology enterprise operating in the optics and optoelectronics industries. The ZEISS Group develops and distributes semiconductor manufacturing equipment, measuring technology, microscopes, medical technology, eyeglass lenses, camera and cine lenses, binoculars, and planetarium technology. With its solutions, the company constantly advances the world of optics and helps shape technological progress. The Research Microscopy Solutions business group is the world's only one-stop manufacturer of light, X-ray, and electron microscope systems. Its portfolio comprises solutions and services for life sciences and materials research as well as industry, education, and clinical practice.

- **FIB-SEM and Ion Microscopes:** Combine 3D imaging and analysis with focused ion beam and femtosecond laser milling to include nanotomography and nanofabrication with ZEISS Crossbeam. Fabricate sub-10 nm structures with ZEISS ORION NanoFab.
- **Scanning Electron Microscopes:** Acquire high-resolution surface information and superior materials contrast for applications in nanotechnology, materials analysis, semiconductor failure analysis, life sciences, and quality assurance.
- **X-ray Microscopes:** Experience nondestructive 3D imaging with industry-best resolution and contrast. With sub-micron and nanoscale 3D XRM systems, realize synchrotron-quality tomographic imaging in your laboratory.
- **Correlative Microscopy:** ZEISS ZEN Connect lets you overlay and organize images from any source to connect multimodal and multiscale data. ZEN Connect has a sample-centric interface that always shows data and metadata in context to support navigation and detailed sample understanding.
- **Confocal and Superresolution Microscopes:** The revolutionary ZEISS Airyscan detector for confocals improves imaging with better signal-to-noise, speed, and resolution. The ZEISS Elyra 7 offers flexibility and gentle superresolution imaging. Elyra 7 with Lattice SIM provides gentle, high-speed superresolution images. ZEISS confocals for materials can provide roughness measurements and topographical characterization.
- **Automated Imaging Systems:** Digitize specimens and create high-quality virtual slides with ZEISS Axio Scan.Z1. Automate live cell imaging with ZEISS Celldiscoverer 7. Imaging well plates and dishes in fluorescence and brightfield has never been easier.
- **Compound Microscopes:** From routine microscopes to fully motorized platforms for simple inspection and advanced research, ZEISS upright and inverted microscopes are configurable to your specific imaging needs.
- **Stereo and Zoom Microscopes:** These stereoscopic and macroscopic products offer large object fields and allow extended working distances, ideal for observing large biological samples or analysis of a variety of materials.
- **Digital Microscopes:** ZEISS Smartzoom 5 is your smart digital microscope, ideal for quality control, quality assurance, and failure analysis applications in virtually every field of industry.
- **Lightsheet Microscopy:** The new ZEISS Lattice Lightsheet 7 makes volumetric imaging of subcellular structures and dynamics over hours and days with minimal photodamage easily accessible through automation and the ability to use standard sample carriers. ZEISS Lightsheet 7 achieves fast and gentle multiview imaging of large living and cleared specimens such as whole model organisms or even whole mouse brains.



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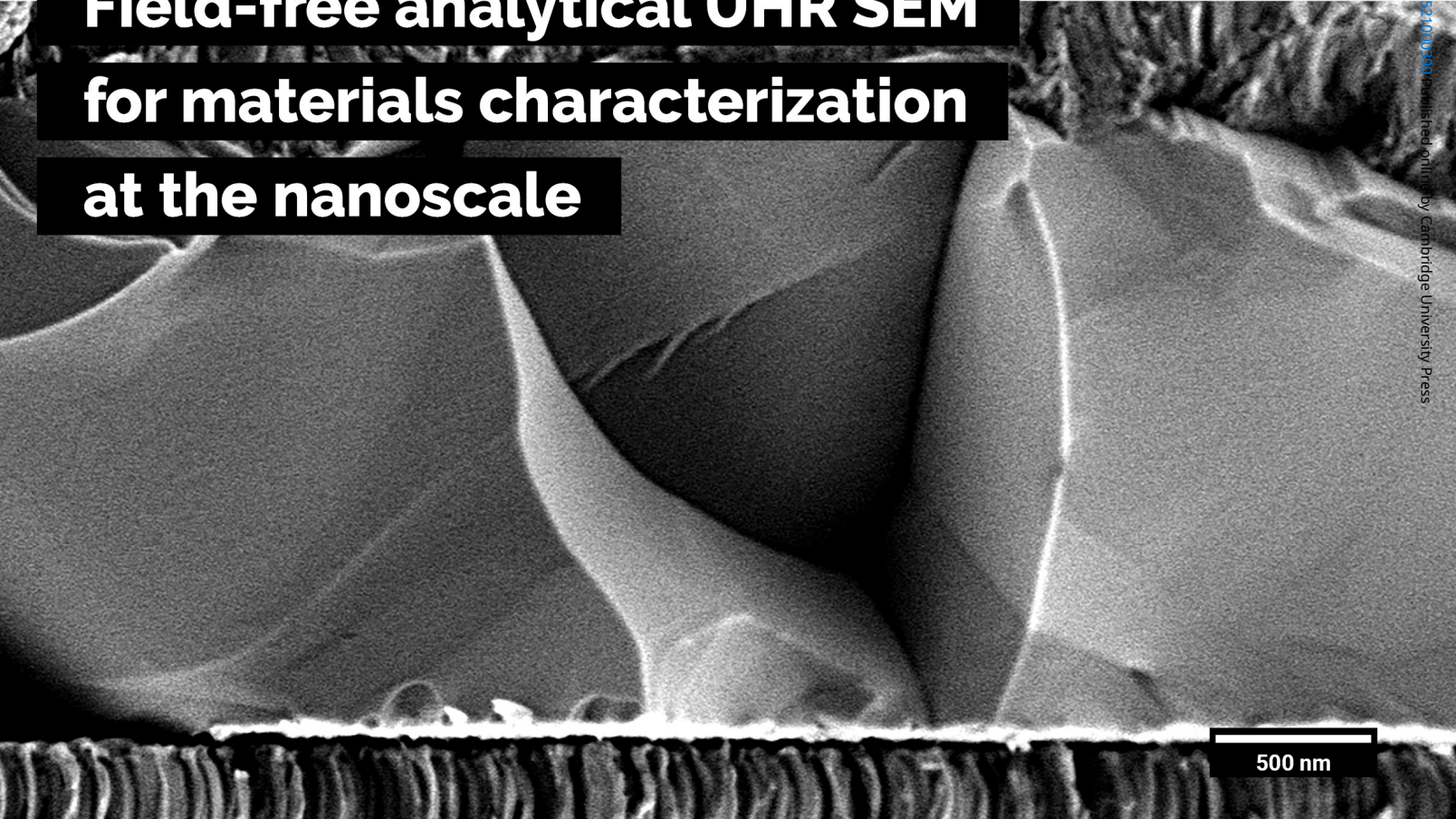
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Field-free analytical UHR SEM for materials characterization at the nanoscale



500 nm

Fracture of solar cell, imaged at 2 keV, E-T detector
Sample courtesy of Center for Solar Energy and Hydrogen Research Baden-Württemberg, Stuttgart

TESCAN CLARA

- ✓ Unique BSE contrast discrimination based on BSEs take off angle and energy, using advanced in column Multidetector design
- ✓ UHR topographical characterization of materials at low beam energies in field-free fashion using Bright Beam™ technology
- ✓ Excellent for imaging beam-sensitive and non-conductive samples
- ✓ Fast setup of electron beam – optimal imaging and analytical conditions guaranteed by In-Flight Beam Tracing™
- ✓ Intuitive and precise live-SEM navigation on the sample at low magnification without the need for an optical navigation camera
- ✓ Effortless operation regardless of a user's experience level guaranteed by intuitive Essence™ software
- ✓ Ultimate topographical nanocharacterization at low landing voltages delivered by combination of BrightBeam™ Technology and optional Beam Deceleration Technology

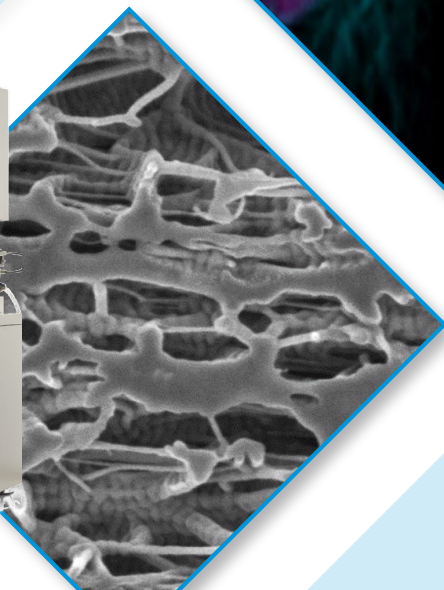
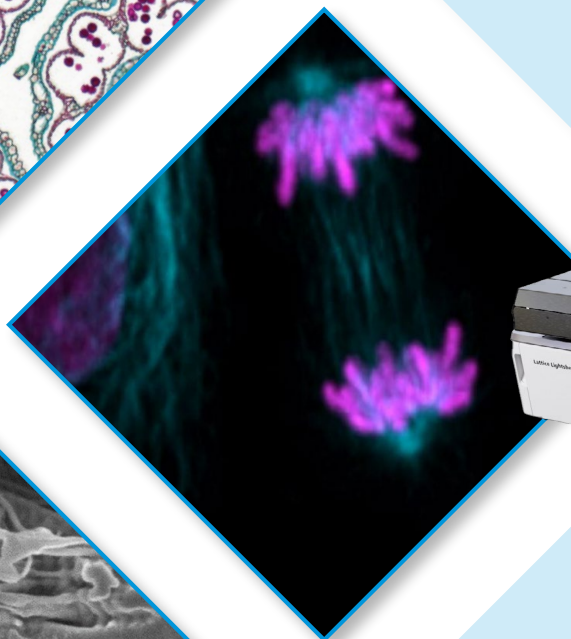
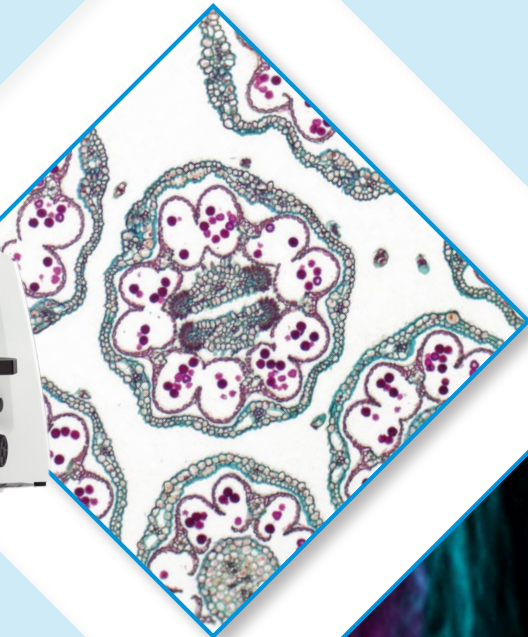


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